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FORM PTO-1449 (Coll.)

ATTY DCKET NO.

SERIAL NUMBER

1-013396-8

09 829 435

LIST OF PATENTS AND PUBLICATIONS  
FOR APPLICANT'S INFORMATION  
STATEMENT

APPLICANT

Yocel ARHUJ, et al

FILING DATE

April 9, 2001

GROUP PART UNIT

2877

## U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
ab	AA	5,969,855	Oct 1999	Ishiwata, et al	359	386
	AB	5,969,853	Oct 1999	Takaoka	359	370
	AC	5,936,253	Aug 1999	Sugaya	250	548
	AD	5,870,191	Feb 1999	Shirley, et al	345	356
	AE	5,814,815	Sep 1998	Matsumoto, et al	250	311
	AF	5,751,475	May 1998	Ishiwata, et al	359	387
	AG	5,619,372	Apr 1997	Hellmuth, et al	359	289
	AH	5,600,440	Feb 1997	Bendall	355	345

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANSLATION
↓	AI	JP 9230247	9/1997	Japan		
	AJ	JP 9179020	7/1997	Japan		
	AK	JP 8004930	4/1996	Japan		

OTHER ART OF SAME VALUE: 10% Reduced Pages 1-2

AI	Philion DW "General Methods for Generating Phase-Shifting Interferometry Algorithms" Applied Optics Vol. 36, 8098, 1997
AM	Phala M "Stray-Light Problem in Phase Contrast Microscopy or Toward Highly Sensitive Phase Contrast Devices: A review" Optical Engineering Vol. 32, 3199

EXAMINER

DATE CONSIDERED

12/16/07

EXAMINER Initial reference considered whether or not citation is in conformance with AIA P 609. If not in conformance and not considered, include copy of this form with next communication to applicant.

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FORM PTO-1449 (CGB)

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LIST OF PATENTS AND PUBLICATIONS  
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## U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
AL	AA	5,159,474	Oct 1992	Frankel, et al	359	29
	AB	5,777,736	Jul 1998	Horton	356	346
	AC	4,653,921	Mar 1987	Kwon	356	353
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	AE					

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
AM	AF	EP 0 555 099	8/1993	Europe		
AN	AG	GB 2,315,700	2/1998	Great Britain		
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## OTHER ART (including Author, Title, Patent, Pubs, etc.)

AO	AI	Golden J. J. "Zernike Test: Analytical Aspects" Applied Optics, Vol. 16, 205 (1977)
AP	AJ	Bruning J. H. et al. "Digital Wavefront Measuring Interferometry for Testing Optical Surfaces and Lenses" Applied Optics, Vol. 13, 2693 (1974)
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DATE CONSIDERED

11/16/03

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FORM PTO-1449 (Colb.)

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## U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
sh	AA	5,171,303	Nov 1995	At et al	356	357	
	AB	5,446,540	Aug 1995	Lin	356	345	
	AC	5,235,587	Apr 1993	Bearden, et al.	369	106	
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	AE	1,190,366	Feb 1980	Doyle	356	346	

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANSLATION
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	AG	JP 7225341	8/1993	Japan			
	AH	JP 6186504	7/1994	Japan			

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sh	AI	Noda T. and Kawata S. "Separation of Phase and Absorption Images in Phase-Contrast Microscopy", Journal of the Optical Society of America A, Vol. 9, 924 (1992)
	AJ	Creath K. "Phase Measurement Interferometry Techniques", Progress in Optics XXVI, 348 (1988)
	AK	Greivenkamp J. L. "Generalized Data Reduction for heterodyne Interferometry", Optical Engineering, Vol. 23, 356 (1984)
	AL	Morgan C. J. "Least Squares Estimation in Phase-Measurement Interferometry", Optics Letters, Vol. 7, 568 (1982)

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4/16/03

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